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Jianwen Zhu; Gajski, D.D.

Design Automation Conference, 2001. Proceedings of the ASP-DAC 2001. Asia and South Pacific , 2001

Page(s): 57 -62

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Casal-Gimenez, J.; Walczowski, L.T.

Electronics, Circuits and Systems, 2001. ICECS 2001. The 8th IEEE International Conference on , Volume: 2 , 2001

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Ardalan, S.M.

Aerospace Conference Proceedings, 2000 IEEE , Volume: 1 , 2000

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Sercel, J.C.; Clymer, T.F.; Heikichs, W.M.

Aerospace Conference, 1999. Proceedings. 1999 IEEE , Volume: 5 , 1999

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6 An ASIC design flow of deep submicron succeeds on first pass

Mair, H.; Liming Xiu

Solid-State and Integrated Circuit Technology, 1998. Proceedings. 1998 5th International Conference on , 1998

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✓ **7 CHDStd-a model for deep submicron design tools**

Cottrell, D.; Mallis, D.; Morrell, J.

Design Automation Conference 1998. Proceedings of the ASP-DAC '98. Asia and South Pacific , 1998

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8 A new algorithm for CAD-directed CMM dimensional inspection

Yueh-Jaw Lin; Murugappan, P.

Robotics and Automation, 1998. Proceedings. 1998 IEEE International Conference on , Volume: 1 , 1998

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9 Mechanism simulation with Working Model

Shih-Liang Wang

Frontiers in Education Conference, 1996. FIE '96. 26th Annual Conference., Proceedings of , Volume: 3 , 1996

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10 A VLSI design management environment

Hodges, S.; Rounce, P.

Design Management Environments in CAD, IEE Colloquium on , 1991

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Gopalakrishnan, B.; Pandiarajan, V.

Systems, Man and Cybernetics, 1990. Conference Proceedings., IEEE International Conference on , 1990

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